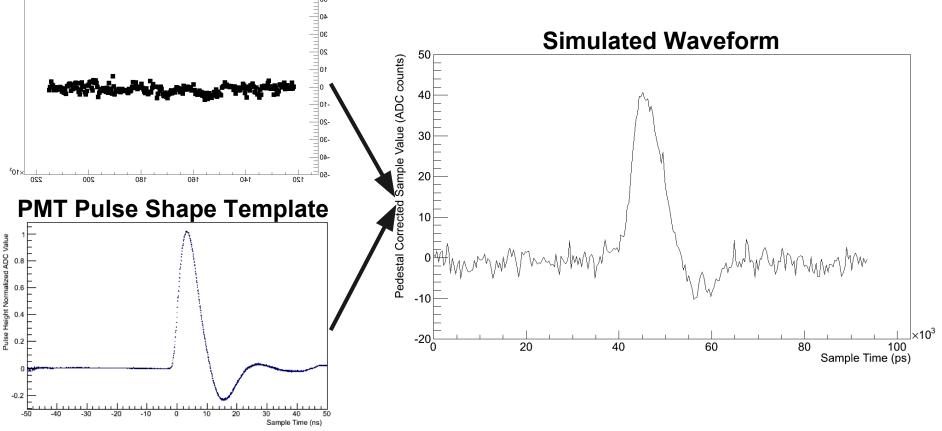
IRS3B Test Setup Update

TOP Meeting, July 16th 2013

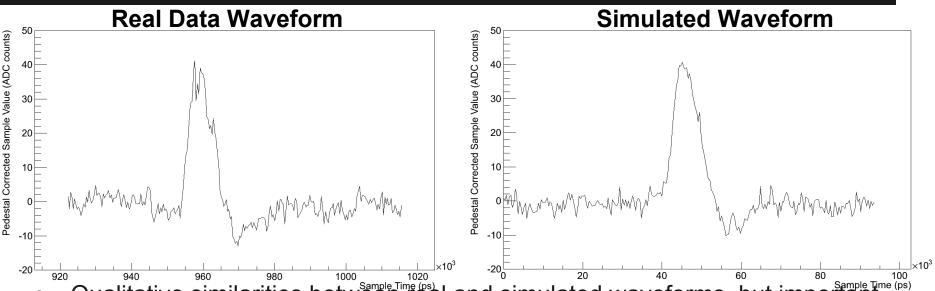
IRS3B Waveform Simulation

Pedestal Waveform



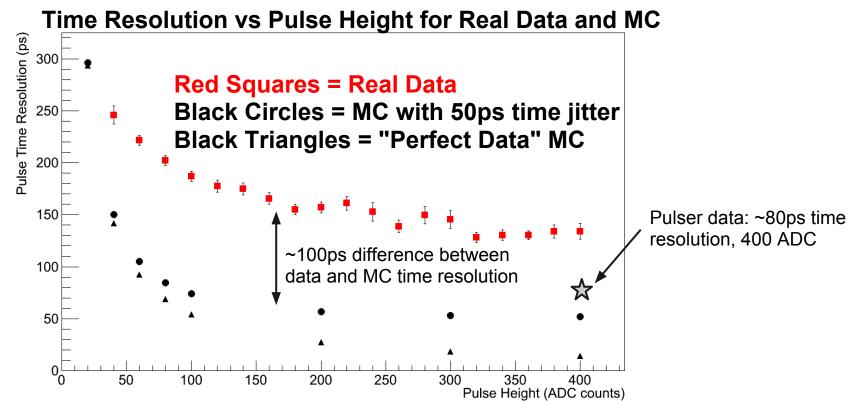
 Simulated waveforms use real pedestal waveforms combined with pulse shape templates averaged from real laser or beam data

Simulated vs Real Waveforms



- Qualitative similarities between real and simulated waveforms, but important of the construction of the
 - Pulse shaping time: slightly different shaping time, need to modify templates but ok for now
 - Non-ideal sampling: including sample-to-sample time variation (sample), ADC non-linearity and sporadic glitches
 - Noise: real pulses may add additional noise above baseline levels
 - **Time jitter**: trigger jitter, sampling phase correction error and PMT transit time spread. Approximated by smearing overall waveform time by ~50ps

Time Resolution Vs Pulse Height

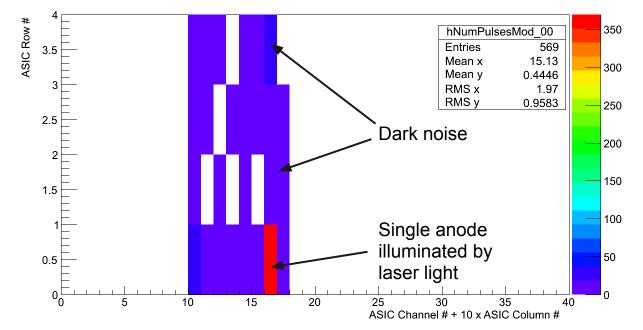


• MC time resolution much better than real data, evidence that there is room for improvement in calibration procedure (ie. gain non-linearity correction)

- Time resolution degrades for < 100 ADC (SNR ~47.5) even for "perfect" MC
 - Indicates noise and analysis method become the limiting factors

Laser Test Setup and Data Taking

Number of Pulses Module 00 ASIC ROW # vs 10 x COL # + CH #



- Laser test setup working well, able to get 1-4% laser hit rates in specific channels with < 0.1% in the remainder, crucial for accurate time resolution and efficiency measurements
- Generally taking combined pulser + laser data, where pulser pulses are injected into a non-adjacent channel on the same ASIC
 - Makes processing tricky, but provides useful cross-check on performance

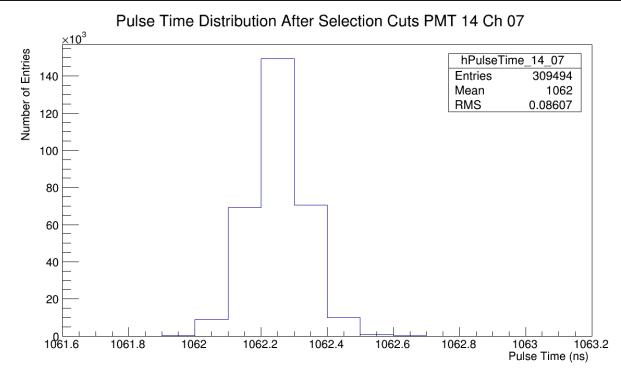
2

Test Setup Sampling Rate Measurement

Module 0 ASIC #	Beam Test Sampling Rate (GHz)	Test Setup Sampling Rate (GHz)
Row 0 Col 0	2.728	2.751
Row 0 Col 1	2.733	2.739
Row 0 Col 2	2.705	2.724
Row 0 Col 3	2.750	2.730
Row 1 Col 0	2.719	2.704
Row 1 Col 1	2.716	2.702
Row 1 Col 2	2.734	2.712
Row 1 Col 3	2.734	2.737

- Pulser data used to measure sampling rate and sample-DTs using same method as used during the beam test
 - See significant differences in measured sampling rates, despite using same configuration files => related to sampling rate stability problem?

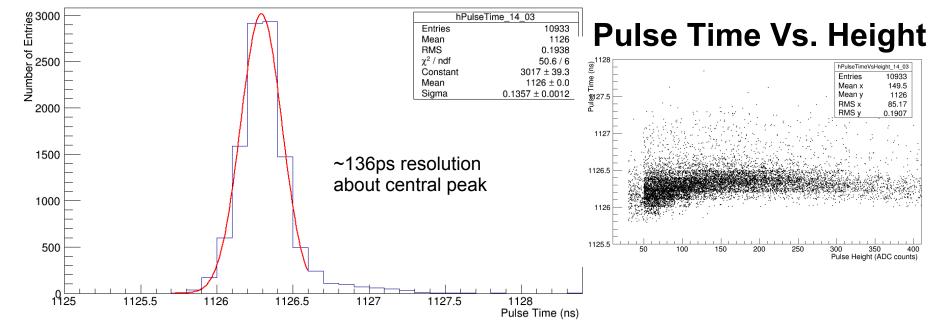
Pulser Time Resolution Measurements



- Pulser time resolutions generally between 70-100ps (table will be posted soon)
- Discrepancy with simulated expectation is significant, need to understand

Laser Pulse Time Resolution Measurements

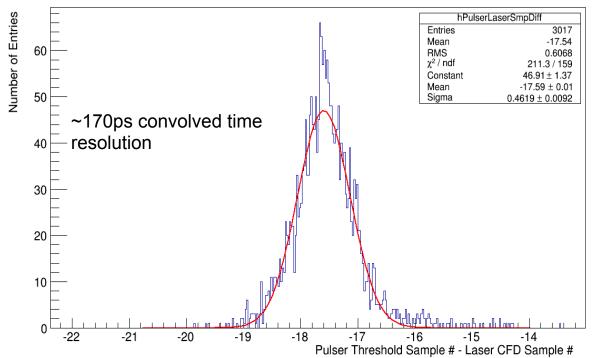
Pulse Time Distribution After Selection Cuts PMT 14 Ch 03



- Straightforward to measure time resolution using established method
- See time walk effect, sample correction becoming increasingly important
 - Small pulses have much worse time resolution, getting most pulses > 100 ADC counts (at same SNR) would significantly help resolution

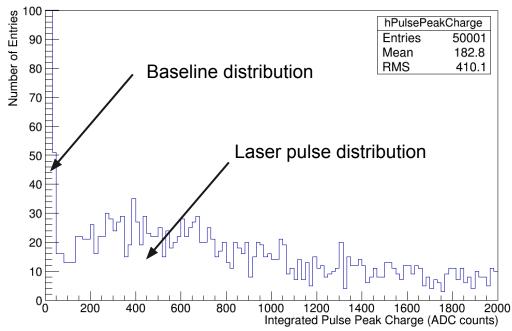
Relative Time Resolution Measurements

Pulser-Laser Sample Difference Distribution



- Can measure laser pulse time with respect to pulser pulser time to cross-check the amount of jitter introduced by the sampling phase correction, CAMAC etc.
- Roughly consistent with alternative measurements, indicates that CAMACbased sampling phase correction not introducing jitter much greater than ~50ps

Laser Pulse Efficiency Measurement



- Can use pulser pulse to predict when laser pulse SHOULD be
- Integrate samples about the expected laser pulse position using forced readouts to get unbiased charge distribution
 - Done at nominal gain (+100V resulted in a few high current events)
 - Ideally can perform absolute efficiency measurement using this method
 - Would like to also perform standard relative efficiency measurement as a cross-check, but this requires modifying the laser system